



ALPHA & OMEGA
SEMICONDUCTOR

AON7400B

30V N-Channel MOSFET

General Description

- Latest Trench Power MOSFET technology
- Very Low $R_{DS(ON)}$ at 4.5V V_{GS}
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

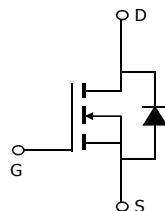
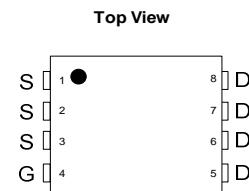
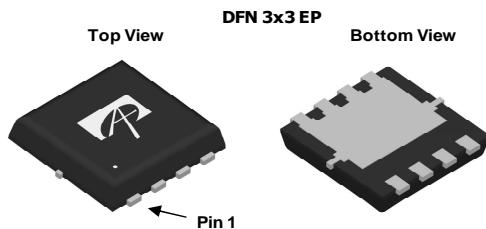
Application

- DC/DC Converters in Computing, Servers, and POL
- Isolated DC/DC Converters in Telecom and Industrial

Product Summary

V_{DS}	30V
I_D (at $V_{GS}=10V$)	30A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 7.5mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 10.5mΩ

100% UIS Tested
100% R_g Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AON7400B	DFN 3x3 EP	Tape & Reel	5000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current <small>$T_C=25^\circ C$</small>	I_D	40 ^I	A
		30 ^G	
		23 ^G	
Pulsed Drain Current ^C	I_{DM}	84	
Continuous Drain Current <small>$T_A=25^\circ C$</small>	I_{DSM}	18	A
		14.5	
Avalanche Current ^C	I_{AS}	27	A
Avalanche energy <small>$L=0.1mH$</small> ^C	E_{AS}	36	mJ
V_{DS} Spike	100ns	V_{SPIKE}	V
Power Dissipation ^B	P_D	24	W
		9.5	
Power Dissipation ^A	P_{DSM}	4.1	W
		2.6	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

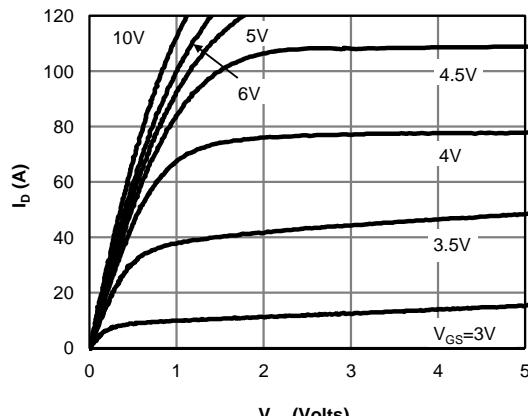
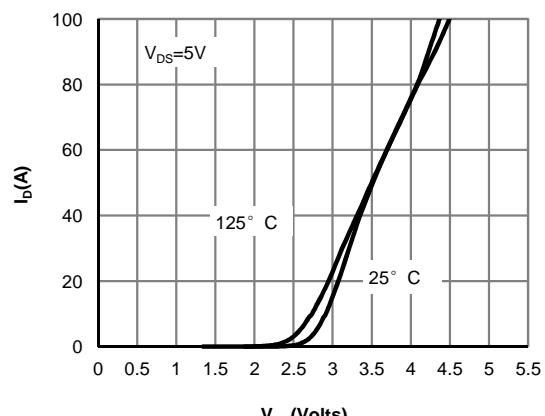
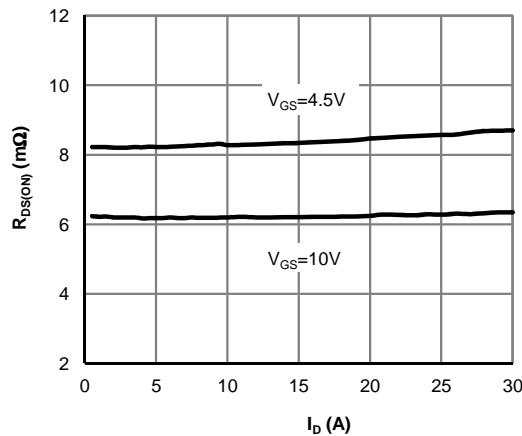
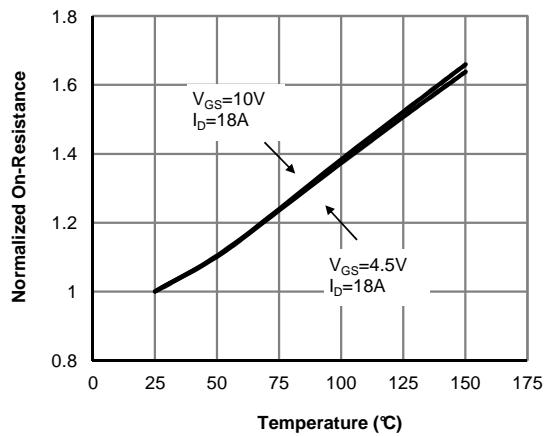
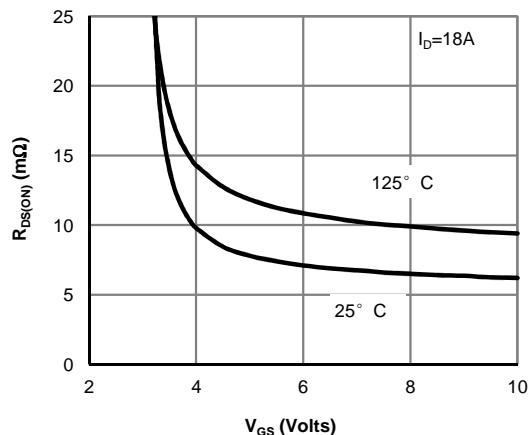
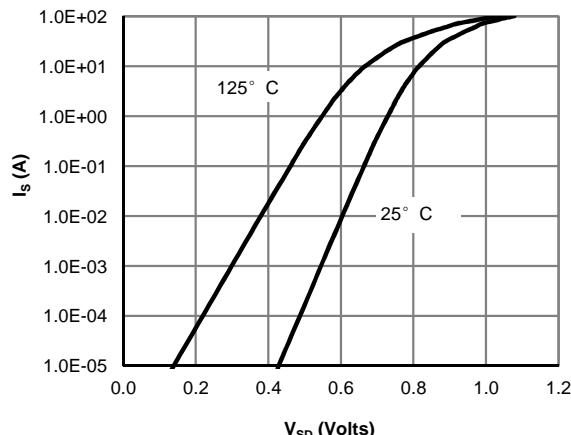
Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	24	30	°C/W
		47	60	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	4.2	5.2	°C/W

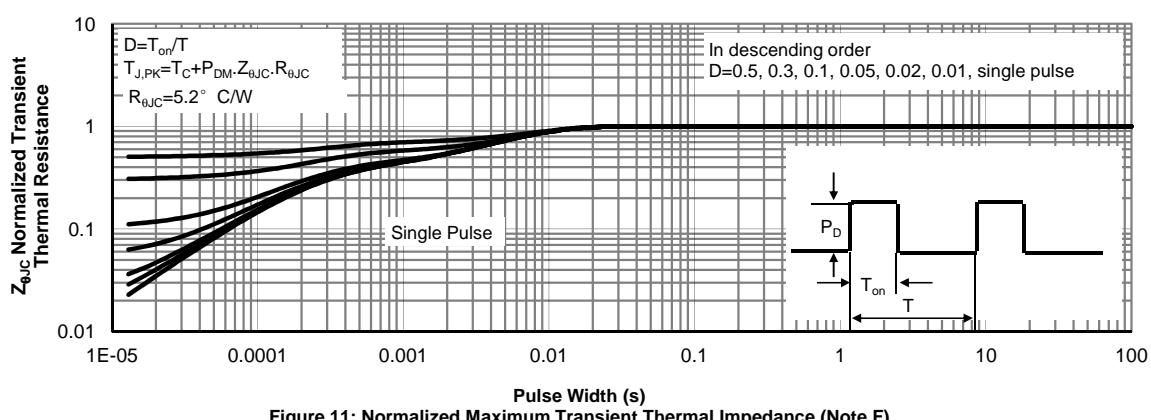
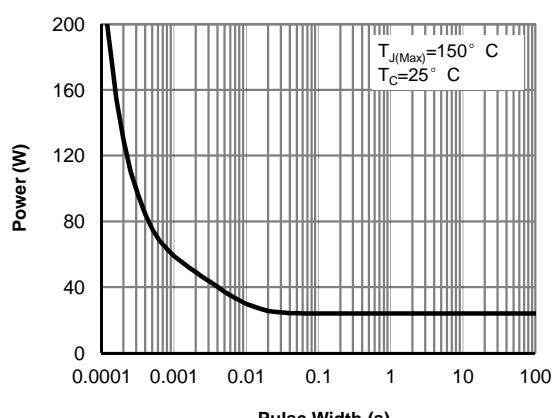
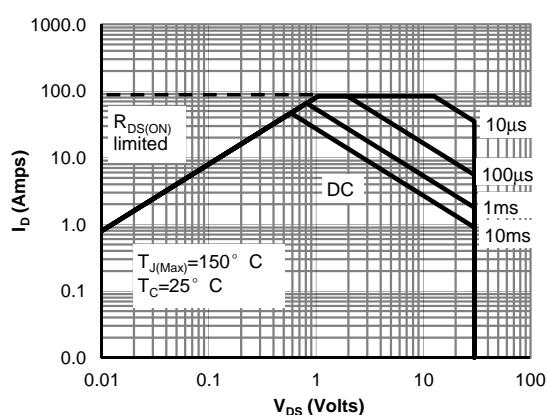
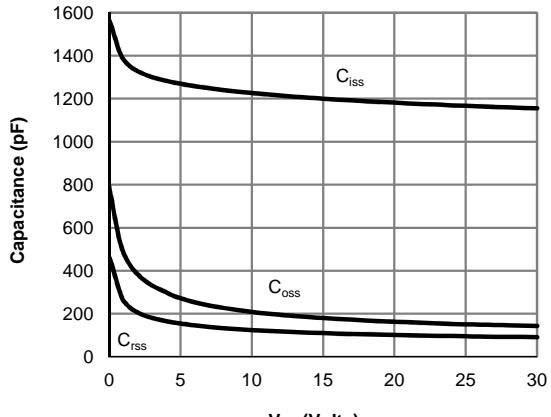
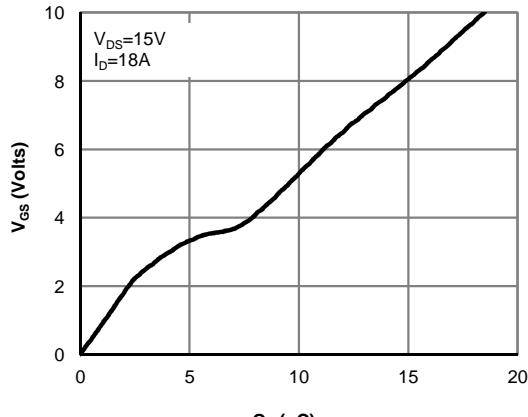
Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{VGS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $\text{T}_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm20\text{V}$			±100	nA
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.5	1.95	2.5	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=18\text{A}$ $\text{T}_J=125^\circ\text{C}$		6.2	7.5	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=18\text{A}$		9.4	11.3	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=18\text{A}$		8.4	10.5	$\text{m}\Omega$
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.72	1	V
I_{S}	Maximum Body-Diode Continuous Current				28	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$	960	1200	1440	pF
C_{oss}	Output Capacitance		125	180	235	pF
C_{rss}	Reverse Transfer Capacitance		65	110	155	pF
R_{g}	Gate resistance	$\text{f}=1\text{MHz}$	0.4	0.9	1.4	Ω
SWITCHING PARAMETERS						
$\text{Q}_{\text{g}}(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=18\text{A}$	10	18.5	26	nC
$\text{Q}_{\text{g}}(4.5\text{V})$	Total Gate Charge		4	8.5	15	nC
Q_{gs}	Gate Source Charge		1	3	8	nC
Q_{gd}	Gate Drain Charge		2	4	10	nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_{\text{L}}=0.83\Omega, \text{R}_{\text{GEN}}=3\Omega$		5.5		ns
t_{r}	Turn-On Rise Time			3.5		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			21.5		ns
t_{f}	Turn-Off Fall Time			3.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=18\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$	6	10	14	ns
Q_{rr}	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=18\text{A}, \text{dI}/\text{dt}=500\text{A}/\mu\text{s}$	9	15.5	22	nC

- A. The value of R_{QJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $\text{R}_{\text{QJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.
- B. The power dissipation P_D is based on $T_{\text{J(MAX)}}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
- C. Single pulse width limited by junction temperature $T_{\text{J(MAX)}}=150^\circ\text{C}$.
- D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{JJC} and case to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{\text{J(MAX)}}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.
- G. The maximum current rating is package limited.
- H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.
- I. The maximum current rating is silicon limited.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


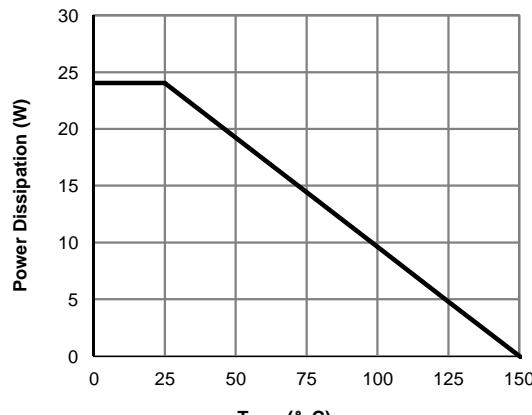
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

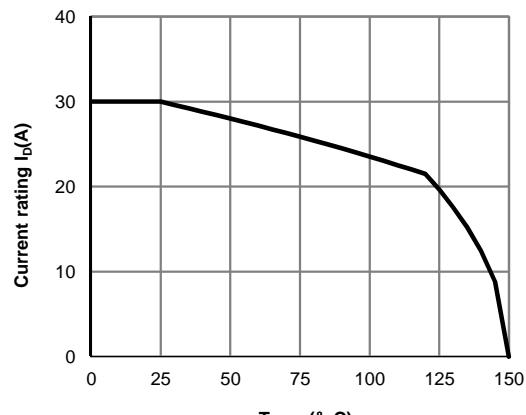


Figure 13: Current De-rating (Note F)

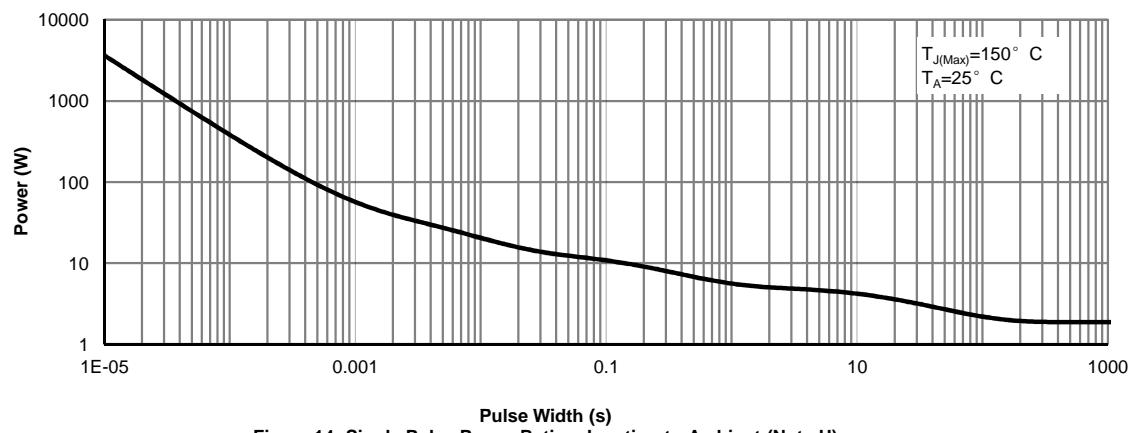


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

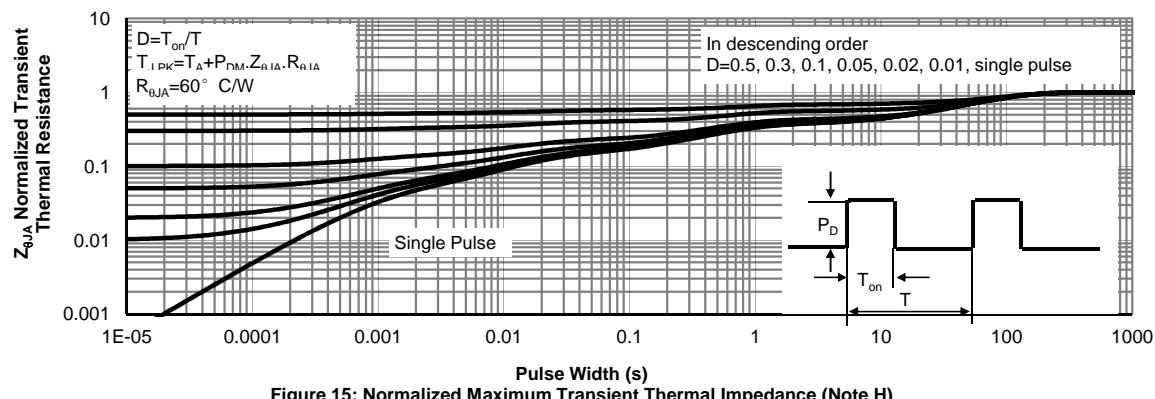
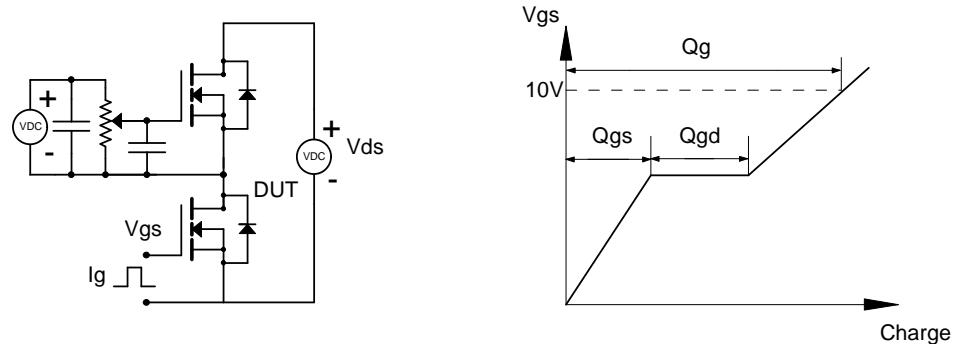
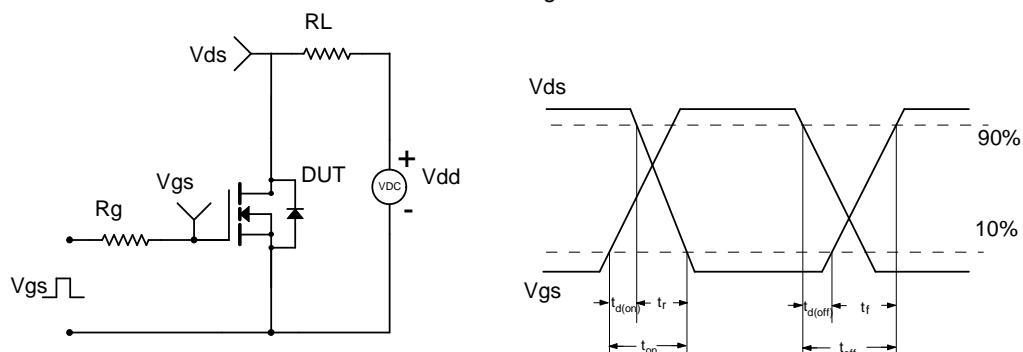
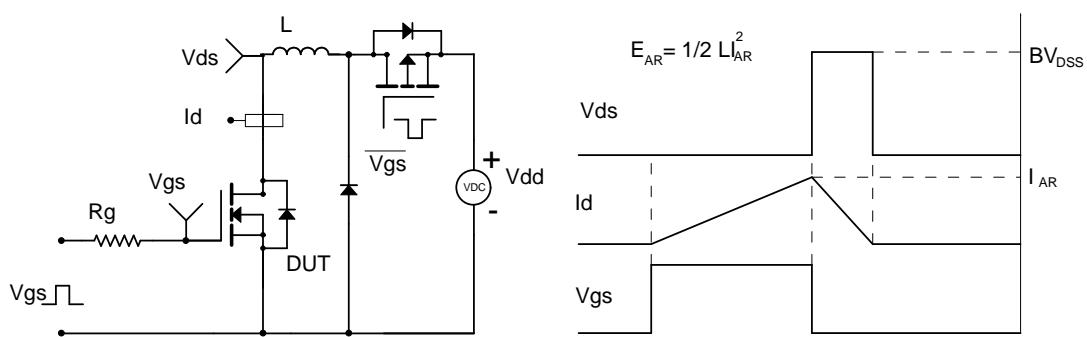


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
